

Uncertainty in the Definition and Calibration of Multiscale Material Models

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- Individual model VVUQ – single model focusing on single length and/or time scales → historical focus
- Multiscale model VVUQ – single model or coupled set of models comprising a simulation operating over multiple length/time scales in concurrent or hierarchical manner → needs attention
- Multiphysics model VVUQ – ensuring that the implementation of a modeling framework spanning multiple physical phenomena is mathematically and physically consistent → virgin territory

See: Panchal, J.H., Kalidindi, S.R., and McDowell, D.L., Computer-Aided Design, Vol. 45, No. 1, 2013, pp. 4–25.

- **Hierarchical Multiscale Model – one way**
 - Uncertainties in model form, initial values, parameters, choice of scales to bridge
 - Typically operates from bottom-up, but model calibration involves combination of bottom-up and top-down information
- **Concurrent Multiscale Model – two way**
 - Uncertainties in model form relate to the way the model form is structured to achieve concurrency
 - Often practically limited to coarse-graining (e.g., same model form, but different DOF) or reduced order models

Note:

- Intrusive or embedded UQ methods are attractive for CMMs

- “Plentiful” Data:
 - Fusion of large scale experiments (e.g., synchrotron tomography) with models
 - Large scale parametric computational runs across a range of random samples/instantiations of microstructures
 - Plentiful data to support training/calibration, and validation
- “Small” Data:
 - Limited number of sensors/measurements
 - Limited number of experiments or expensive simulations
 - More common scenario in materials design and development

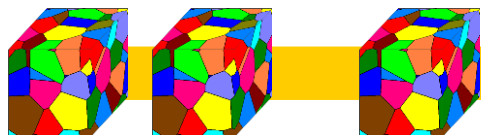
UQ is useful for each case:

- Plentiful – UQUP, statistical learning algorithms that track uncertainty
- Small – algorithmic decision support to guide choice of next experiment or simulation



1. Generate multiple SVEs
based on predefined
distributions of key
microstructure attributes

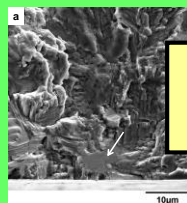
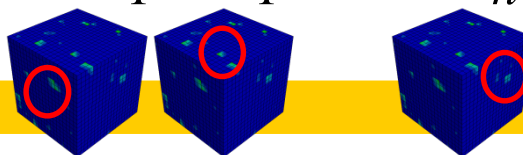
$\Omega_1, \Omega_1, \dots, \Omega_n$



Groeber et al. 2007, IN100

2. Identify EV response of SVEs
via simulation

$\Omega_1, \Omega_1, \dots, \Omega_n$



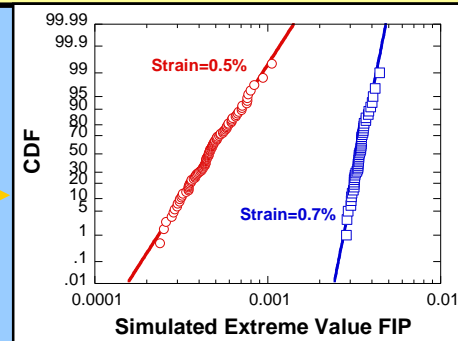
Experimental
Calibration/Validation

6(a). Iterate
materials design

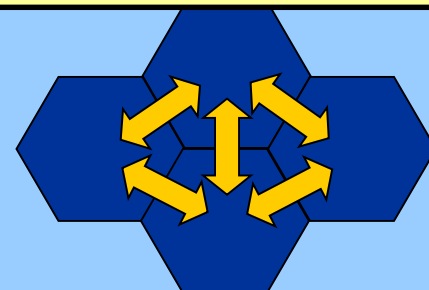
6(b). Select top
candidates for
experimental
evaluation

5. Identify extreme value correlated
attributes key to response and rank
microstructures

3. Characterize EV
distributions of key response
parameters



4. Characterize correlated
microstructure attributes
coincident with the EV
response (EV marked
correlation functions)

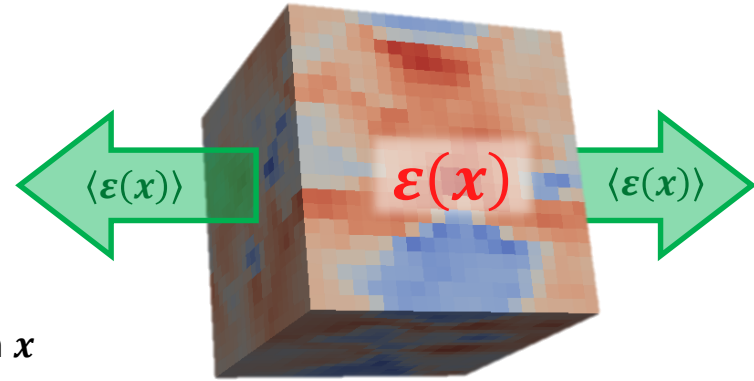


C. Przybyla,
GT, 2010

The **Materials Knowledge System** (MKS) is a localization technique to determine local response (eg. ε_{11}) given macroscopic applied condition

$$\varepsilon(\mathbf{x}) = \mathbf{a}(\mathbf{x}) \langle \varepsilon(\mathbf{x}) \rangle$$

- $\mathbf{a}(\mathbf{x})$: 4th rank localization tensor at spatial location \mathbf{x}
- $\langle \rangle$: ensemble average over RVE



MKS

Now expand $\mathbf{a}(\mathbf{x})$:

$$\begin{aligned} \varepsilon(\mathbf{x}) = & \left(\mathbf{I} - \int_R \int_H \boldsymbol{\alpha}(\mathbf{r}, n) m(\mathbf{x} + \mathbf{r}, n) d\mathbf{n} d\mathbf{r} \right. \\ & \left. + \int_R \int_R \int_H \int_H \tilde{\boldsymbol{\alpha}}(\mathbf{r}, \mathbf{r}', n, n') m(\mathbf{x} + \mathbf{r}, n) m(\mathbf{x} + \mathbf{r} + \mathbf{r}', n') d\mathbf{n} d\mathbf{n}' d\mathbf{r} d\mathbf{r}' - \dots \right) \langle \varepsilon(\mathbf{x}) \rangle \end{aligned}$$

Microstructure function:

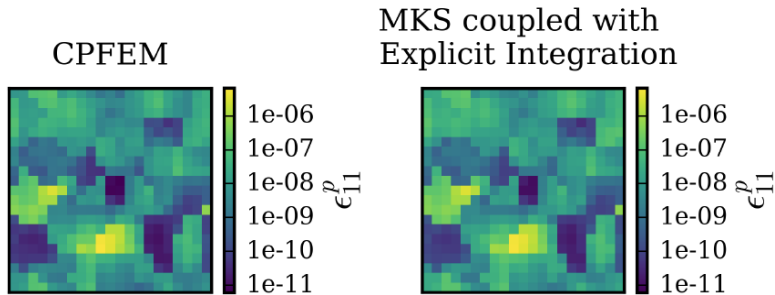
$$m(\mathbf{x}, n) = \sum_L \sum_s M_s^L Q_L(n) X_s(\mathbf{x})$$

Influence function:

$$\boldsymbol{\alpha}(\mathbf{r}, n) = \sum_L \sum_t \mathbf{A}_t^L Q_L(n) \chi_t(\mathbf{r})$$

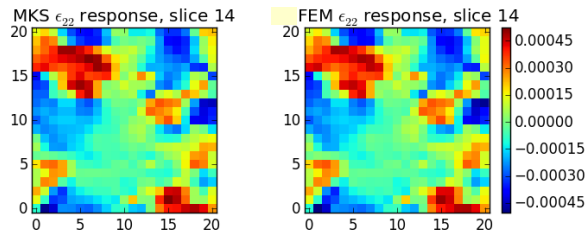
$Q_L(n)$: orthonormal Fourier basis
 $X_s(\mathbf{x})$: indicator basis

Kalidindi (2012), Adams (2012), Kröner (1986), Yabansu (2014)

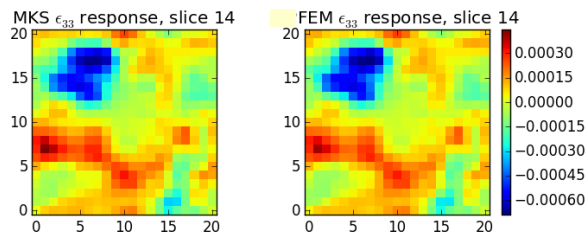


MKS prediction of ϵ tensor for basal textured α -Ti:

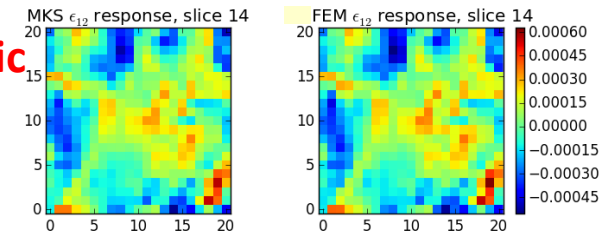
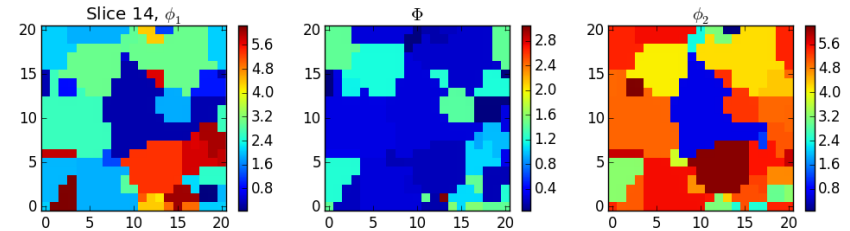
Epistemic approx. error



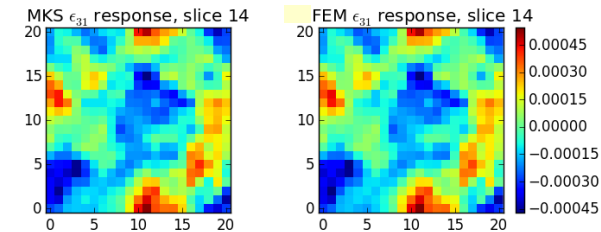
ϵ_{22} mean error: 0.20%
 ϵ_{22} max error: 1.2%



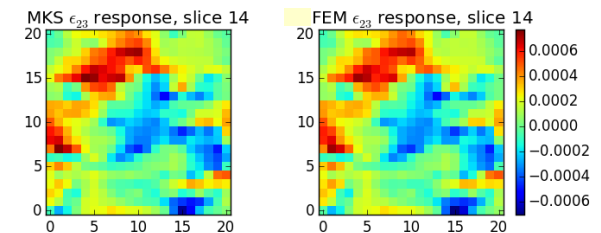
ϵ_{33} mean error: 0.22%
 ϵ_{33} max error: 1.3%



ϵ_{12} mean error: 0.35%
 ϵ_{12} max error: 2.1%



ϵ_{13} mean error: 0.29%
 ϵ_{13} max error: 3.2%

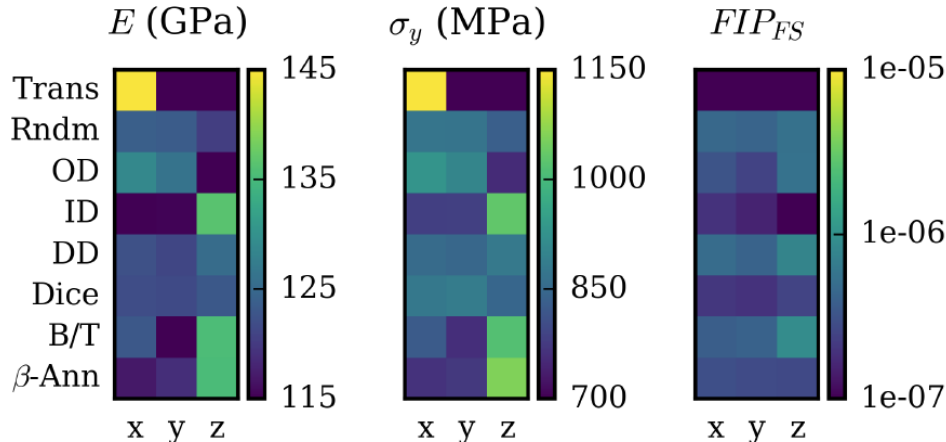


ϵ_{23} mean error: 0.29%
 ϵ_{23} max error: 1.8%

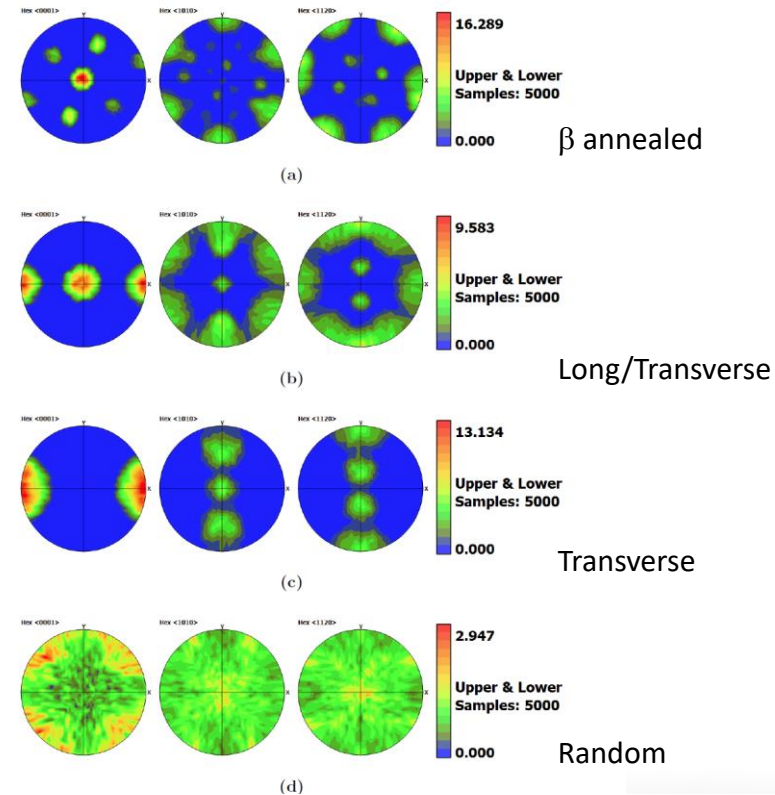
Priddy, M.W., Paulson, N.H., Kalidindi, S.R., and McDowell, D.L., International Journal of Fatigue, Vol. 104, 2017, pp. 231-242.

Multiple design objectives include elastic stiffness, directional yield strength and HCF resistance.

(E) , (σ_y) , and FIP_{FS}

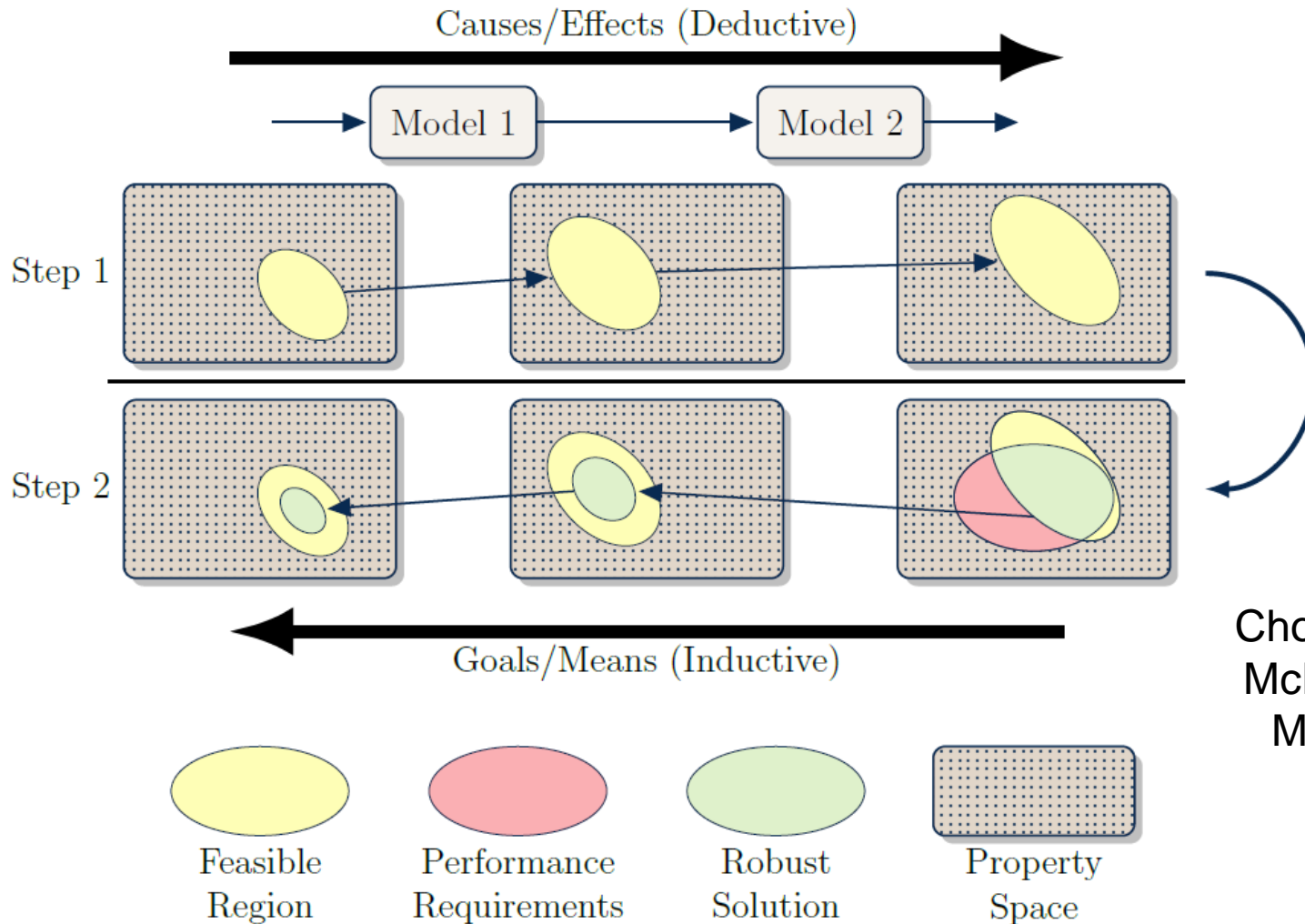


Mean (E, σ_y) and FIP_{FS} for 0.10 probability level for each of 8 textures and three orthogonal uniaxial loading conditions.



Kern, P.C., Priddy, M.W., Ellis, B.D., and McDowell, D.L., "pyDEM: A Generalized Implementation of the Inductive Design Exploration Method," *Materials & Design*, Vol. 134, 2017, pp. 293-300.

P. C. Kern, M. W. Priddy, B. D. Ellis, D.L. McDowell, *pydem 1.0.0*, 2017: <https://github.com/materialsinnovation/pydem>

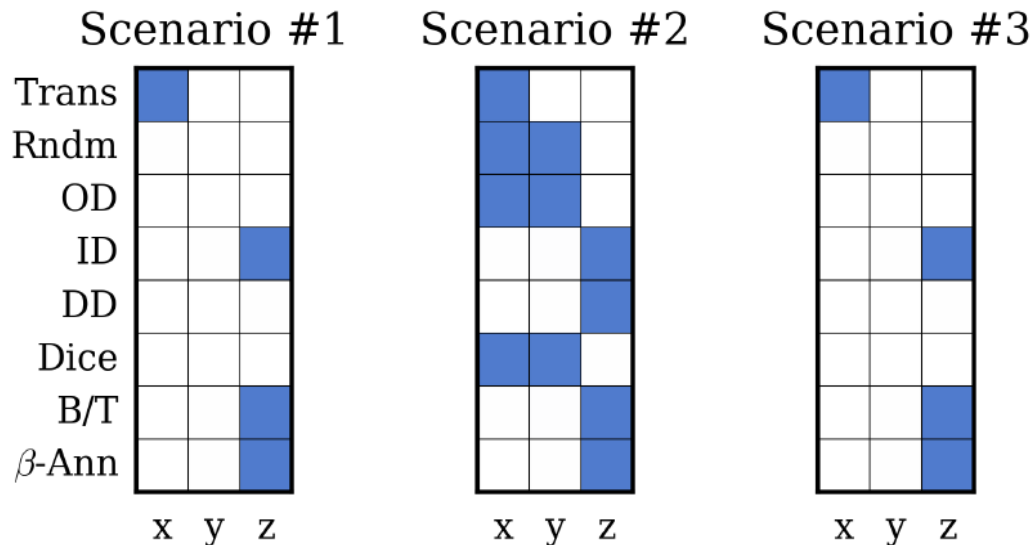


Choi, 2005; Choi,
McDowell, Allen,
Mistree, 2008

Table 6.3: Texture IDEM Design Requirements

Scenario	E (mean)	σ_y (mean)	FIP_{FS}
#1	> 130 GPa	–	$< 5 \times 10^{-6}$
#2	–	> 900 MPa	$< 5 \times 10^{-6}$
#3	> 130 GPa	> 900 MPa	$< 5 \times 10^{-6}$

Max FIP_{FS} at 10%
cumulative probability



Priddy PhD Thesis, 2016

Two-dimensional representation of the feasible space for each of the design space for each design scenario applied to each of the 8 textures and 3 loading directions. Blue boxes indicate satisfaction of the performance requirements.